Docket No.: J&R-0694

MAR 1 0 2006

## CERTIFICATION OF MAILING OR TRANSMISSION

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 or facsimile transmitted to the U.S. Patent and Trademark Office on the date shown below

March 10, 2006

Date

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.

09/922,479

Confirmation No: 7212

Applicant

Thomas Zettler August 3, 2001

Filed Title

Method and Device for Testing an Integrated Circuit, Integrated

Circuit to be Tested, and Wafer with a Large Number of Integrated

Circuits to be Tested

Art Unit

2138

Examiner

Phung M. Chung

Docket No.

J&R-0694

Customer No. 24131

## RESPONSE

Hon. Commissioner for Patents

Sir:

Responsive to the Office Action dated February 13, 2006, the following remarks are made:

In deference to the restriction requirement on page 2 of the above-identified Office Action, applicants elect group I, claims 1 - 4, 6 - 17, 19 - 23 and 29 for prosecution at this time.

In view of the foregoing, the early issuance of an Action on the merits of claims 1 - 4, 6 - 17, 19 - 23 and 29 is solicited.

Respectfully submitted.

Werner H. Stemer (34,956)

Date: March 10, 2006

Lerner Greenberg Stemer LLP

Post Office Box 2480

Hollywood, FL 33022-2480

Tel: (954) 925-1100

Fax: (954) 925-1101

/am